## Data Sheet

## FEATURES

1.5 pF off source capacitance
$<1 \mathrm{pC}$ charge injection
33 V supply range
$120 \Omega$ on resistance
Fully specified at $\pm 15 \mathrm{~V},+12 \mathrm{~V}$
No V L supply required
3 V logic-compatible inputs
Rail-to-rail operation
14-lead TSSOP and 12-lead LFCSP
Typical power consumption < $0.03 \mu \mathrm{~W}$

## APPLICATIONS

Automatic test equipment

## Data acquisition systems

Battery-powered systems
Sample-and-hold systems
Audio signal routing
Video signal routing
Communication systems

## GENERAL DESCRIPTION

The ADG1204 is a complementary metal-oxide semiconductor (CMOS) analog multiplexer, comprising four single channels designed on an $i$ CMOS (industrial CMOS) process. $\mathrm{iCMOS}^{\star}$ is a modular manufacturing process that combines high voltage CMOS and bipolar technologies. It enables the development of a wide range of high performance analog ICs capable of 33 V operation in a footprint that no previous generation of high voltage devices has been able to achieve. Unlike analog ICs using conventional CMOS processes, $i$ CMOS components can tolerate high supply voltages while providing increased performance, dramatically lower power consumption, and reduced package size.

The ultralow capacitance and charge injection of this multiplexer makes it an ideal solution for data acquisition and sample-andhold applications, where low glitch and fast settling are required. Fast switching speed coupled with high signal bandwidth makes the device suitable for video signal switching. iCMOS construction ensures ultralow power dissipation, making the device ideally suited for portable and battery-powered instruments.

## FUNCTIONAL BLOCK DIAGRAM



Figure 1.

The ADG1204 switches one of four inputs to a common output, D, as determined by the 3-bit binary address lines: A0, A1, and EN. Logic 0 on the EN pin disables the device. Each switch conducts equally well in both directions when on and has an input signal range that extends to the supplies. In the off condition, signal levels up to the supplies are blocked. All switches exhibit break-before-make switching action.

## PRODUCT HIGHLIGHTS

1. $\quad 1.5 \mathrm{pF}$ off capacitance ( $\pm 15 \mathrm{~V}$ supply).
2. $<1 \mathrm{pC}$ charge injection.
3. 3 V logic-compatible digital inputs: $\mathrm{VIH}=2.0 \mathrm{~V}, \mathrm{VIL}=0.8$ V.
4. No VL logic power supply required.
5. Ultralow power dissipation: $<0.03 \mu \mathrm{~W}$.
6. 14-lead TSSOP and 12-lead, $3 \mathrm{~mm} \times 3 \mathrm{~mm}$ LFCSP packages.

Rev. C

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3/16-Rev. B to Rev. C
Changed LFCSP_VQ to LFCSP Throughout
Changes to Figure 3 8
Updated Outline Dimensions ..... 15
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## SPECIFICATIONS

## DUAL SUPPLY

$\mathrm{V}_{\mathrm{DD}}=15 \mathrm{~V} \pm 10 \%, \mathrm{~V}_{\mathrm{SS}}=-15 \mathrm{~V} \pm 10 \%, \mathrm{GND}=0 \mathrm{~V}$, unless otherwise noted.
Table 1.


| Parameter | $25^{\circ} \mathrm{C}$ | $\begin{aligned} & \text { Y Version } \\ & -40^{\circ} \mathrm{C} \text { to } \\ & +85^{\circ} \mathrm{C} \end{aligned}$ | $\begin{aligned} & -40^{\circ} \mathrm{C} \text { to } \\ & +125^{\circ} \mathrm{C} \\ & \hline \end{aligned}$ | Unit | Test Conditions/Comments |
| :---: | :---: | :---: | :---: | :---: | :---: |
| POWER REQUIREMENTS | 0.001 |  | 1.0 | $\mu \mathrm{A}$ typ $\mu \mathrm{A} \max$ | $\mathrm{V}_{\mathrm{DD}}=+16.5 \mathrm{~V}, \mathrm{~V}_{S S}=-16.5 \mathrm{~V}$ |
| IDD |  |  | Digital inputs $=0 \mathrm{~V}$ or $\mathrm{V}_{\mathrm{DD}}$ |  |
| IDD |  |  |  |  |
|  | 170 |  |  |  | $\mu \mathrm{A}$ typ | Digital inputs $=5 \mathrm{~V}$ |
|  |  |  |  | 285 | $\mu \mathrm{A}$ max |  |
| Iss | 0.001 |  |  | $\mu \mathrm{A}$ typ | Digital inputs $=0 \mathrm{~V}$ or $\mathrm{V}_{\mathrm{DD}}$ |
|  |  |  | 1.0 | $\mu \mathrm{A}$ max |  |
| Iss | 0.001 |  |  | $\mu \mathrm{A}$ typ | Digital inputs $=5 \mathrm{~V}$ |
|  |  |  | 1.0 | $\mu \mathrm{A}$ max |  |

${ }^{1} \mathrm{Y}$ version temperature range is $-40^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$.
${ }^{2}$ Guaranteed by design, not subject to production test.

## SINGLE SUPPLY

$\mathrm{V}_{\mathrm{DD}}=12 \mathrm{~V} \pm 10 \%, \mathrm{~V}_{\mathrm{SS}}=0 \mathrm{~V}, \mathrm{GND}=0 \mathrm{~V}$, unless otherwise noted.
Table 2.


${ }^{1} \mathrm{Y}$ version temperature range is $-40^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$.
${ }^{2}$ Guaranteed by design, not subject to production test.

## ABSOLUTE MAXIMUM RATINGS

$\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$, unless otherwise noted.
Table 3.

| Parameter | Rating |
| :---: | :---: |
| $\mathrm{V}_{\text {D }}$ to $\mathrm{V}_{\text {Ss }}$ | 35 V |
| $V_{\text {DD }}$ to GND | -0.3 V to +25 V |
| $V_{\text {ss }}$ to GND | +0.3 V to -25 V |
| Analog Inputs ${ }^{1}$ | $\begin{aligned} & V_{S S}-0.3 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{DD}}+0.3 \mathrm{~V} \text { or } \\ & 30 \mathrm{~mA} \text {, whichever occurs first } \end{aligned}$ |
| Digital Inputs ${ }^{1}$ | GND -0.3 V to $\mathrm{V}_{\mathrm{DD}}+0.3 \mathrm{~V}$ or 30 mA , whichever occurs first |
| Peak Current, S or D | 100 mA (pulsed at 1 ms , $10 \%$ duty cycle maximum) |
| Continuous Current | 45 mA |
| Operating Temperature Range Automotive (Y Version) | $-40^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ |
| Storage Temperature Range | $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ |
| Junction Temperature | $150^{\circ} \mathrm{C}$ |
| 14-Lead TSSOP, $\theta_{\mathrm{JA}}$ Thermal Impedance (4-Layer Board) | $112^{\circ} \mathrm{C} / \mathrm{W}$ |
| 12-Lead LFCSP, $\theta_{\mathrm{JA}}$ Thermal Impedance | $80^{\circ} \mathrm{C} / \mathrm{W}$ |
| Reflow Soldering Peak Temperature, Pb Free | $260^{\circ} \mathrm{C}$ |

[^0]Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

Only one absolute maximum rating can be applied at any one time.

## ESD CAUTION

|  | ESD (electrostatic discharge) sensitive device. <br> Charged devices and circuit boards can discharge <br> without detection. Although this product features <br> patented or proprietary protection circuitry, damage <br> may occur on devices subjected to high energy ESD. <br> Therefore, proper ESD precautions should be taken to <br> avoid performance degradation or loss of functionality. |
| :--- | :--- |

## PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS



Figure 2. TSSOP Pin Configuration


NOTES

1. NC = NO CONNECT. DO NOT CONNECT TO THIS PIN.
2. THE EXPOSED PAD MUST BE TIED

TO SUBSTRATE, $\mathrm{V}_{\mathrm{SS}}$.
Figure 3. LFCSP Pin Configuration

Table 4. Pin Function Descriptions

| Pin No. |  |  |  |
| :--- | :--- | :--- | :--- |
| TSSOP | LFCSP | Mnemonic | Description |
| 1 | 11 | A0 | Logic Control Input. <br> Active High Digital Input. When low, the device is disabled and all switches are off. <br> 2 |
|  |  | EN |  |
| When high, Ax logic inputs determine on switches. |  |  |  |
| 3 | 1 | VSS | Most Negative Power Supply Potential. |
| 4 | 2 | S1 | Source Terminal. Can be an input or an output. |
| 5 | 3 | S2 | Source Terminal. Can be an input or an output. |
| 6 | 4 | D | Drain Terminal. Can be an input or an output. |
| 7 to 9 | 5 | NC | No Connection. |
| 10 | 6 | S4 | Source Terminal. Can be an input or an output. |
| 11 | 7 | S3 | Source Terminal. Can be an input or an output. |
| 12 | 8 | VDD | Most Positive Power Supply Potential. |
| 13 | 9 | GND | Ground (0 V) Reference. |
| 14 | 10 | A1 | Logic Control Input. |

## TRUTH TABLE

Table 5.

| EN | A1 | A0 | S1 | S2 | S3 | S4 |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- |
| 0 | X | X | 0 | Off | Off | Off |
| 1 | 0 | 1 | On | Off | Off | Off |
| 1 | 1 | 0 | Off | On | Off | Off |
| 1 | 1 | 1 | Off | Off | On | Off |
| 1 | Off | On |  |  |  |  |

## TYPICAL PERFORMANCE CHARACTERISTICS



Figure 4. On Resistance as a Function of $V_{D}\left(V_{s}\right)$, Dual Supply


Figure 5. On Resistance as a Function of $V_{D}\left(V_{S}\right)$, Dual Supply


Figure 6. On Resistance as a Function of $V_{D}\left(V_{S}\right)$, Single Supply


Figure 7. On Resistance as a Function of $V_{D}\left(V_{S}\right)$ for Different Temperatures, Dual Supply


Figure 8. On Resistance as a Function of $V_{D}\left(V_{S}\right)$ for Different Temperatures, Single Supply


Figure 9. Leakage Currents as a Function of Temperature, Dual Supply


Figure 10. Leakage Currents as a Function of Temperature, Single Supply


Figure 11. IDD vs. Logic Level


Figure 12. Charge Injection vs. Source Voltage


Figure 13. Transition Times vs. Temperature


Figure 14. Off Isolation vs. Frequency


Figure 15. Crosstalk vs. Frequency


Figure 16. On Response vs. Frequency


Figure 17. THD $+N$ vs. Frequency


Figure 18. Off Capacitance vs. Source Voltage


Figure 19. On Capacitance vs. Source Voltage


Figure 20. Capacitance vs. Source Voltage, Single Supply

TEST CIRCUITS


Figure 21. On Resistance


Figure 22. Off Leakage


Figure 23. On Leakage


Figure 24. Address to Output Switching Times


Figure 25. Break-Before-Make Time Delay


Figure 26. Enable-to-Output Switching Delay


Figure 27. Charge Injection


Figure 28. Off Isolation


Figure 29. Bandwidth

## TERMINOLOGY

$\mathrm{I}_{\mathrm{DD}}$
The positive supply current.
Iss
The negative supply current.
$V_{D}\left(V_{s}\right)$
The analog voltage on Terminal D and Terminal S .
$\mathbf{R}_{\text {ON }}$
The ohmic resistance between D and S .
$\mathbf{R}_{\text {flat(on) }}$
Flatness is defined as the difference between the maximum and minimum value of on resistance, as measured over the specified analog signal range.
Is (OFF)
The source leakage current with the switch off.

## $I_{D}$ (OFF)

The drain leakage current with the switch off.
$\mathrm{I}_{\mathrm{D}}, \mathrm{I}_{\mathrm{S}}(\mathrm{ON})$
The channel leakage current with the switch on.
$V_{\text {INL }}$
The maximum input voltage for Logic 0 .
$V_{\text {INH }}$
The minimum input voltage for Logic 1.
$\mathrm{I}_{\text {INL }}\left(\mathrm{I}_{\text {INH }}\right)$
The input current of the digital input.
Cs (OFF)
The off switch source capacitance, which is measured with reference to ground.
$\mathrm{C}_{\mathrm{D}}$ (OFF)
The off switch drain capacitance, which is measured with reference to ground.

## $\mathrm{C}_{\mathrm{D}}, \mathrm{C}_{\mathrm{s}}(\mathrm{On})$

The on switch capacitance, measured with reference to ground.
$\mathrm{C}_{\mathrm{IN}}$
The digital input capacitance.
ton (EN)
The delay between applying the digital control input and the output switching on.
toff (EN)
The delay between applying the digital control input and the output switching off.
$t_{\text {trans }}$
The delay time between the $50 \%$ and $90 \%$ points of the digital input and switch on condition when switching from one address state to another.

## Charge Injection

A measure of the glitch impulse transferred from the digital input to the analog output during switching.

## Off Isolation

A measure of unwanted signal coupling through an off switch.

## Crosstalk

A measure of unwanted signal that is coupled through from one channel to another as a result of parasitic capacitance.

## Bandwidth

The frequency at which the output is attenuated by -3 dB .

## On Response

The frequency response of the on switch.

## Insertion Loss

The loss due to the on resistance of the switch.
Total Harmonic Distortion + Noise (THD + N)
The ratio of the harmonic amplitude plus noise of the signal to the fundamental.

## OUTLINE DIMENSIONS



Figure 32. 14-Lead Thin Shrink Small Outline Package [TSSOP] (RU-14)
Dimensions shown in millimeters


COMPLIANT TO JEDEC STANDARDS MO-220-WEED.
Figure 33. 12-Lead Lead Frame Chip Scale Package [LFCSP]
$3 \mathrm{~mm} \times 3 \mathrm{~mm}$ Body and 0.75 mm Package Height (CP-12-4)
Dimensions shown in millimeters

## ORDERING GUIDE

| Model $^{1}$ | Temperature Range | Package Description | Package Option |
| :--- | :--- | :--- | :--- |
| ADG1204YRUZ | $-40^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | 14-Lead Thin Shrink Small Outline Package [TSSOP] | RU-14 |
| ADG1204YRUZ-REEL | $-40^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | 14-Lead Thin Shrink Small Outline Package [TSSOP] | RU-14 |
| ADG1204YRUZ-REEL7 | $-40^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | 14-Lead Thin Shrink Small Outline Package [TSSOP] | RU-14 |
| ADG1204YCPZ-500RL7 | $-40^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | 12-Lead Lead Frame Chip Scale Package [LFCSP] | $\mathrm{CP}-12-4$ |
| ADG1204YCPZ-REEL7 | $-40^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | 12-Lead Lead Frame Chip Scale Package [LFCSP] | CP-12-4 |

[^1]
## NOTES


[^0]:    ${ }^{1}$ Overvoltages at $\mathrm{IN}, \mathrm{S}$, or D are clamped by internal diodes. Current must be limited to the maximum ratings given.

[^1]:    ${ }^{1} Z=$ RoHS Compliant Part.

